

CLAIMS:

1. (currently amended) An apparatus for testing at least one first integrated circuit (IC) and at least one second IC, comprising:

a first tester adapted to test the at least one first IC with a first test procedure;

a second tester adapted to test the at least one first IC with a second test procedure simultaneously while the first tester tests the at least one second IC with the first test procedure, wherein the first and second test procedures are adapted to test at least some different IC parameters, wherein the first tester is coupled to the second tester; and

a single handler coupled to the first and second testers;

wherein the first tester is adapted to calibrate the second tester.

3. (currently amended) The apparatus according to Claim 1 ~~2~~, wherein the second tester is adapted to submit a request for calibration to the first tester.

4. (currently amended) The apparatus according to Claim 1 ~~2~~, wherein the first tester is adapted to calibrate the second tester at predetermined time intervals or when ambient temperature has changed by a predetermined amount.

5 - 20 (canceled)

21. (currently amended) A method of testing at least one first integrated circuit (IC) and at least one second IC in an apparatus comprising a first tester and a second tester coupled to a single handler, the method comprising:

coupling the first tester to the second tester;

testing the first IC with a first test procedure using the first tester; and testing the second IC with the first test procedure simultaneously while testing the first IC's with a second test procedure using the second tester, wherein testing IC's with the first test procedure comprises testing at least some different IC parameters than testing IC's with the second test procedure;

further comprising calibrating the second tester with the first tester and/or calibrating the first tester with the second tester.

23. (currently amended) The method according to Claim 21 ~~22~~, wherein the calibrating is in response to a request for calibration from the first or second tester.

24. (currently amended) The method according to Claim 21 ~~22~~, wherein the first tester is adapted to calibrate the second tester at predetermined time intervals or when ambient temperature has changed by a predetermined amount.

25 – 33 (canceled)